

**5th EUropean Failure Analysis  
NETwork EUFANET workshop**

**Diagnostic ATPG and CAD  
approaches for IC analysis**

October 12, EUFANET Workshop at ESREF 2005

# Workshop program

- **17h40** Welcome and EUFANET status update (Philippe Perdu, Romain Desplats, CNES and Felix Beaudoin, THALES)
- **17h55** Standard ATPG analysis flow used at Infineon and statistical Scan Test Analysis (SSTA) for analysis purposes (Markus Gruetzner, Infineon)
- **18h10** Truth table analysis (Mickael Moreau, ST Grenoble)
- **18h25** Knights CAD Navigation, Review and New developments (Michael Bruegel, Knights)
- **18h40** FA-Navigation (Kume Toshihiro, Hamamatsu)
- **18h55** Bringing Closer the Logical and Physical Worlds for Device Analysis (Jean-Philippe Roux, Credence)
- **19h10** Debate on Diagnostic ATPG and CAD approaches for IC analysis
- **19h30** Closing remarks

# EUFANET key points



EUFANET do not coordinate European FA but help people to Keep in touch and to boost technical exchanges between them

## ■ Key dates

- EUFANET kick off (2001)
- Email Forum (2002)
- Web site (2003)

No fees

# EUFANET Status update

- 158 members
  - Should be officially renewed (legal status)
  - Board election (by email, 2006)
  - Forum discussion (32 public, ?? Privates)
- WEB site improvement
  - 350 useful links (database for FA)
  - Monthly update
- Legal status (according to 1901 French Law)
- 6th EUFANET Workshop on Optical Localization Techniques (March 2006)

# Useful Links

European Failure Analysis Network

[Useful links][[Educational](#)][[FA labs](#)][[Equipements](#)]

EUFANET Info

Technical stuff

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## What's in this page?

**Useful Links** section provides a hyperlink database which includes all FA aspects relevant to FA people. The object is that all related information can be found **Rapidly, Easily and Directly**.

## Items

### General Information

Conferences, Societies and On-line Publications, including conferences, symposias, societies, associations, organizers, etc.

Laboratories, including FA manufacturers and service societies, R. & D laboratories in industries and in universities.

General FA, including general introduction on FA techniques and process.

Selected Websites, including the hyperlinks in both electronic and other domains .

Failure Analysis Process, all stuff have been classed according to the four steps in FA process.

Electrical Diagnosis is the measurement of all relevant electrical parameters and it is a critical part of systematic failure analysis.

Sample Preparation is an intermediate process step that must be completed before the localization and characterization of faults.

Fault Localization is to isolate the exact physical location of the failsite.

Physical Characterization is the final major step in a root-cause of the failure. This stage involves inspecting the isolated areas of the die to find the responsible defect.

# 6th EUFANET Workshop on Optical Localization Techniques

- Paris, March 16-17 (To be confirmed)
- 1rst day:
- 9h15 to 9h30 Welcome
- 9h30 to 12h30 Static Emission Microscopy and Thermography techniques
- 12h30 to 14h00 Lunch
- 14h00 to 17h00 Dynamic Emission Microscopy techniques
- 17h00 to 20h00 Buffet with sponsors
- 2nd day:
- 9h00 to 12h00 Static Laser Based techniques
- 12h00 to 13h30 Lunch
- 13h30 to 16h30 Dynamic Laser Based techniques
- 16h30 to 16h45 Conclusion

- WEB site [www.eufanet.org](http://www.eufanet.org)
- To subscribe just send an email to [subscribe@eufanet.org](mailto:subscribe@eufanet.org), subject "subscription"
- Would you like to join the board? Just send an email to EUFANET board ([board@eufanet.org](mailto:board@eufanet.org))